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Practitioner's Socket No. 1012-125(2001-023)

PATENT

#### IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Wang et al.

Application No.: 09/954,449 Filed: 09/17/2001

Group No.: 2856 Examiner: Unknown

For: RAPID THROUGHPUT SURFACE TOPOGRAPHICAL ANALYSIS

**Assistant Commissioner for Patents** 

Washington, D.C. 20231

#### INFORMATION DISCLOSURE STATEMENT

Applicants submit this statement in accordance with their duty of disclosure under 37 CFR 1.56 and 1.97-1.98. The submission made herewith is in no way intended as an admission that the cited items constitute material prior art or otherwise would render the claims unpatentable in any way. The submission also is in no way intended to substitute for the Examiner's own independent investigation.

Copies of the references together with a listing on forms PTO/SB/08A and PTO/SB/08B are submitted herewith. Applicants respectfully solicit the Examiner's consideration of the cited references and entry thereof into the record of this application. Applicants are also submitting copies of references cited in a search report (copy enclosed).

No fees are believed to be due, however, if any fee is due with the filing of

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# INFORMATION DISPLOSURE, STATEMENT BY APPENDANT

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Sheet 1 of 6

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Application Number	09/954,449				
Filing Date	09/17/2001				
First Named Inventor	Youqi Wang				
Group Art Unit	2856				
Examiner Name	Unknown				
Attorney Docket Number	1012-125(2001-023)				

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			WO 01/79949		Symyx Technologies, Inc.	10/25/2001		

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<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<sup>&</sup>lt;sup>1</sup> Unique citation designation number. <sup>2</sup> See attached Kinds of U.S. Patent Documents. <sup>3</sup> Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). <sup>4</sup> For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. <sup>5</sup> Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. <sup>6</sup> Applicant is to place a check mark here if English language Translation is attached.

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Group Art Unit 2856 Unknown **Examiner Name** 

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### INFORMATION DISCLOSURE STATEMENT BY APPLICA

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Initials	No.1	Office <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> ( <i>if known</i> )	Applicant of Cited Document	Cited Document MM-DD-YYYY	Passages or Refevant Figures Appear	T6	
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Examiner	Cite	F	oreign Patent Do		Name of Patentee or	Date of Publication of	Pages, Columns, Lines, Where Relevant	
Initials	No.1	Office <sup>3</sup>	Number <sup>4</sup>	Kind Code <sup>5</sup> ( <i>if know</i> n)	Applicant of Cited Document	Cited Document MM-DD-YYYY	Passages or Relevant Figures Appear	T6
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Application Number	09/954,449			
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				U.S. PATENT DOC	UMENTS	
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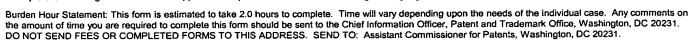
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Sheet	11	of	0	Attorney Docket Number	1012-125(2001-023)

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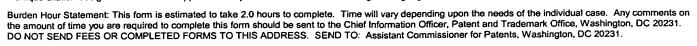
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Signature	Considered	

<sup>\*</sup>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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1012-125(2001-023)

2856

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Patent and Trademark U.S. DEPARTMENT OF COMMERCE respond to a collection of information unless it contains a valid OMB control number. Under the Paperwork Reduction Act of 199 Complete if Known Substitute for form 1449B/PTO **Application Number** 09/954,449 INFORMATION DISCLOS 09/17/2001 Filing Date First Named Inventor Youqi Wang STATEMENT BY APPLICANT

Group Art Unit

Examiner Name

Attorney Docket Number

		OTHER PRIOR ART NON PATENT LITERATURE DOCUMENTS	
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Method of Using Same" filed on May 26, 2000



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STATEMENT BY APPENDE

Complete if Known				
Application Number	09/954,449			
Filing Date	09/17/2001			
First Named Inventor	Youqi Wang			
Group Art Unit	2856			
Examiner Name	Unknown			
Attorney Docket Number	1012-125(2001-023)			

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Examiner Initials	Cite No.1					
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